

<b>Notice of References Cited</b>	Application/Control No. 10/657,273	Applicant(s)/Patent Under Reexamination CHEN, SINN-WEN	
	Examiner John P. Sheehan	Art Unit 1742	Page 1 of 1

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	U	Machine Translation of Japanese Patent Document No. 9-3576, January 1997, Nomura et al.
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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